B.Tech

## MID SEMESTER EXAMINATION

**MARCH 2019** 

## EC310 Testing and diagnosis of digital system design

Time: 90 Minutes

Max. Marks: 25

Note: All questions carry equal marks.

Assume suitable missing data, if any

All symbols and abbreviations have their usual meanings.

Q.1 [i]A gate level fan-out free realization of a circuit has 20 inputs and 2 outputs. What is the minimum number of tests we will need to test this circuit?

[ii]If a fault f1 dominates fault f2, and the fault f2 dominates a fault f3, which of these faults can be deleted to reduce the fault list for fault detection? Explain why.

[iii] Count the total number of possible single stuck at fault sites in Figure 1. (2)

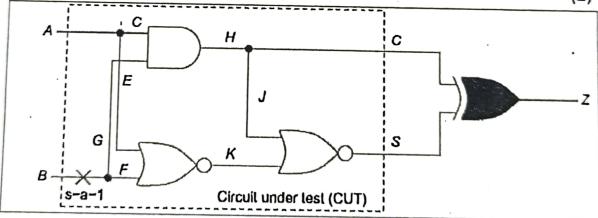


Figure 1

Q.2 In Figure 2, use the PODEM algorithm to test for a SA1 on the output of gate 6. Write on the figure and explain the sequence of decisions. (5)

P.T.O.

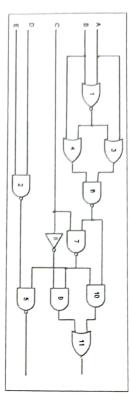


Figure 2

Q :3 that detect the SSL fault x1 stuck-at-1 in N. [i] Let N be a nonredundant logic circuit that realizes the x1(x2 + x4x5). Use the Boolean difference to find all test vectors following Boolean function: z = (x1 + x'2)(x1 + x'2x'3 + x4x5)' +

equivalent fault collapsing. [ii] In Figure 2, determine the collapse ratio after applying

Q.4 [i] Write differences between distinguishing sequence and

(1)

tree and find the distinguishing sequences. [ii] For the state table shown in Table 1, draw the distinguishing

homing sequence

and find all shortest homing sequences. [iii] For the state table shown in Table 1, draw the homing tree (2)

Table 1

Present State (PS)	Next State (NS), Output(Z)	(Z)
	Input X=0	Input X=1
Α	C,0	A,1
В	A,1	в,0
С	D,0	B,1
D	B,1	D,0

## Q.5 In Figure 3,

be tested according to the Checkpoint Theorem. [i] Enumerate the minimal set of single stuck-at faults that must (3)

[ii] Show that the two faults d s-a-0 and  ${f g}$  s-a-1 are equivalent.

(2)

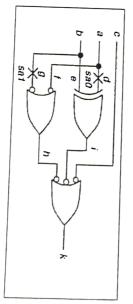


Figure 3